

Active Galactic Nuclei

LOW-RESOLUTION X-RAY SPECTROSCOPY

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Outline

- ⦿ AGN X-ray spectral features overview
- ⦿ CCD resolution spectral fitting
- ⦿ Examples

Active Galactic Nuclei

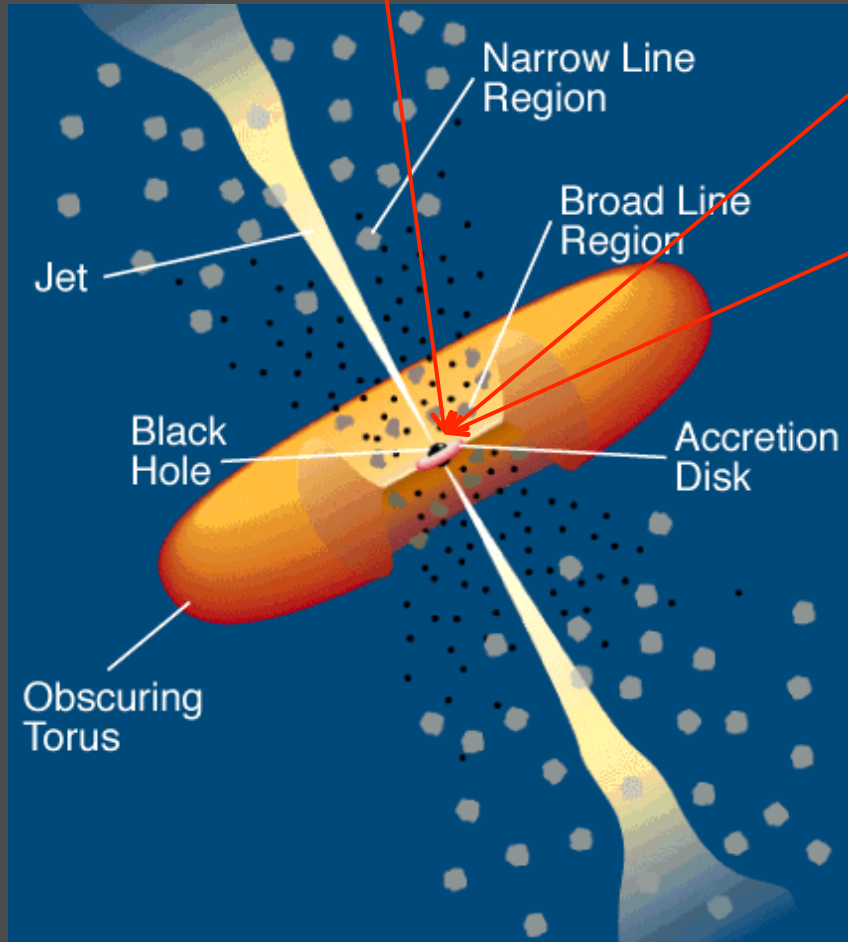
- ⊙ Powered by accretion onto supermassive ($M > 10^6$ solar mass) black hole
- ⊙ Accretion disk temperature $\sim 10^{5-6}$ K \rightarrow in UV
 - Multi-temperature disk
- ⊙ Accretion disk forms a corona ala the Sun which inverse-Compton scatters UV photons from accretion disk to X-rays
 - Results in a power-law X-ray spectrum
 - Cuts off at kT of corona
- ⊙ A “torus” of obscuring gas and dust modifies the spectrum

Quintessential AGN model

Seyfert 1

Seyfert 1.5

Seyfert 2



Type 1 AGN have broad and narrow optical lines. Type 2 AGN have only narrow optical lines. Type 2 AGN often show evidence of obscuration in the X-ray band and sometimes broad lines are seen in polarized light. Explanation: a torus is obscuring the line of sight in type-2 AGN, some flux is scattered around the torus by ionized gas. Or torus may be clumpy (helps explain AGN that change from type-1 to type-2).

Radio-quiet AGN are called Seyferts.

X-ray Continuum in an AGN

Photons have lower energy than KE of electrons

Compton y parameter:

(avg. fractional energy change per scat.)(mean # of scats.)

Simple derivation of IC power-law (Rybicki & Lightman 1979)

$$A = E'/E$$

After k scatterings, energy of photon $E_k = EA^k$

Prob. of k scatterings $\sim \tau^k$

$$F(E_k) = F(E) \tau^k$$

$$A^k = E_k/E$$

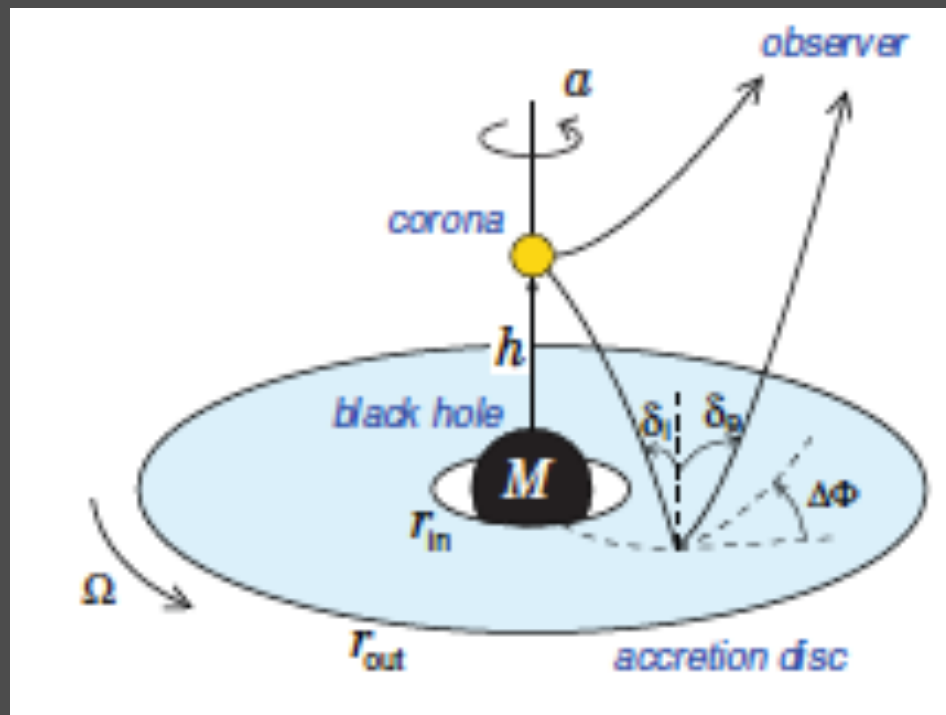
$$k \ln A = \ln(E_k/E)$$

$$\tau^k = \tau^{[\ln(E_k/E)/\ln A]} = (E_k/E)^{[\ln \tau \ln(E_k/E)/\ln A / \ln(E_k/E)]}$$

$$F(E_k) = F(E) (E_k/E)^{(\ln \tau / \ln A)} = F(E) (E_k/E)^{-\alpha}$$

Multiple IC scatterings produces a power-law spectrum

“Lamp Post” model



Dovciak et al. 2011, X-ray Universe Conference

Absorption

$$dF = -n\sigma(E)Fdr \quad \sigma = \text{cross section}$$

$$F = F_0 \exp\left[-\sigma \int n(r)dr\right]$$

Transmission through region of constant density:

$$F = \exp[-nr\sigma(E)]F_0$$

$$\text{Column density} = N_H = \int n(r)dr$$

$$F/F_0 = \exp(-N_H\sigma) = \exp(-\tau)$$

Optically thin = $\tau < 1$

Optically thick = $\tau > 1$

X-ray Cross Sections

X-ray absorption in inter-stellar material mostly due to K-shell photoelectric absorption.

For a given element, $\sigma(E) = 0$ below edge energy, $\propto E^{-3}$ above

Electron scattering $\sigma_T = 6.65 \times 10^{-25} \text{ cm}^{-2}$

Scattering is relevant when $N_H \sigma_T \sim 1$

$$N_H > 1/\sigma_T = 1 \times 10^{24} \text{ cm}^{-2}$$

X-ray Cross Section by Element

$$\sigma = \sum_i Z_i \sigma_i$$

Z_i = abundance of element
 i relative to H

Hence N_H gives H column density

Element	Z (rel. abund.)
H	1.00
He	0.0977
C	3.63e-4
N	1.12e-4
O	8.51e-4
Ne	1.23e-4
Na	2.14e-6
Mg	3.80e-5
Al	2.95e-6
Si	3.55e-5
S	1.62e-5
Fe	4.68e-5
Ni	1.78e-6

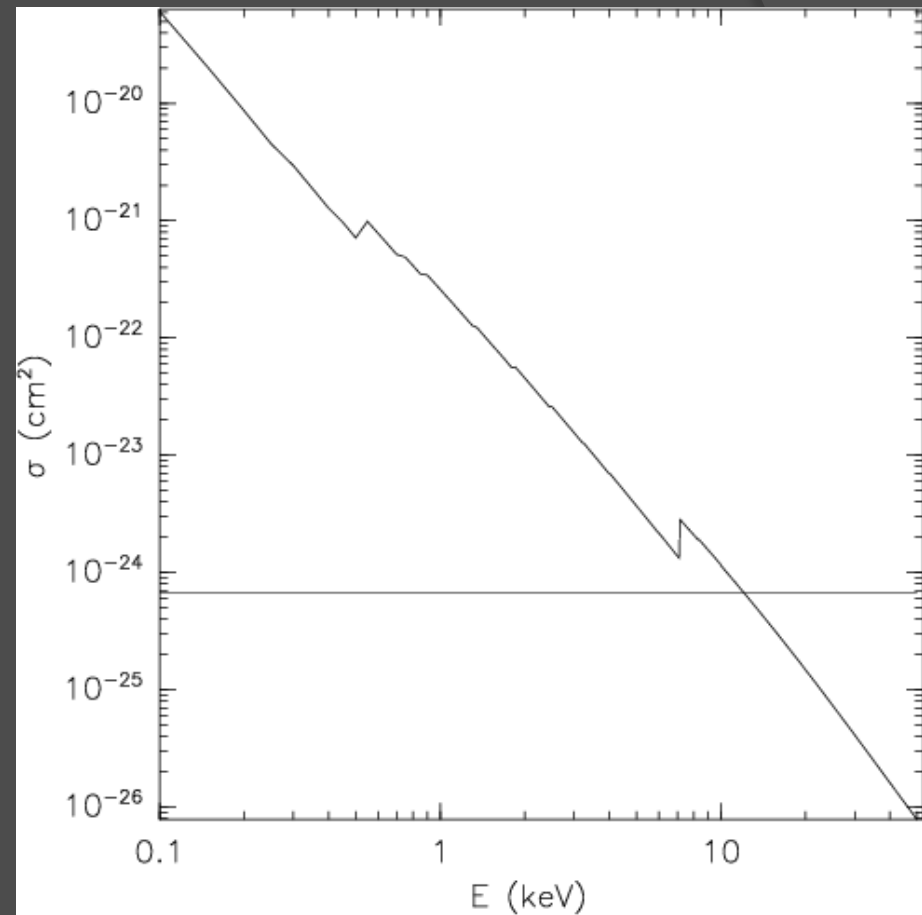
$\sigma(E)$

Optically thin case

$E < \sim 30 \text{ keV}$, $N_{\text{H}} < 10^{24} \text{ cm}^{-2}$

$\exp(-N_{\text{H}}\sigma_{\text{abs}})\exp(-N_{\text{H}}\sigma_{\text{T}})$

$\sigma(E) = \sigma_{\text{abs}} + \sigma_{\text{T}}$

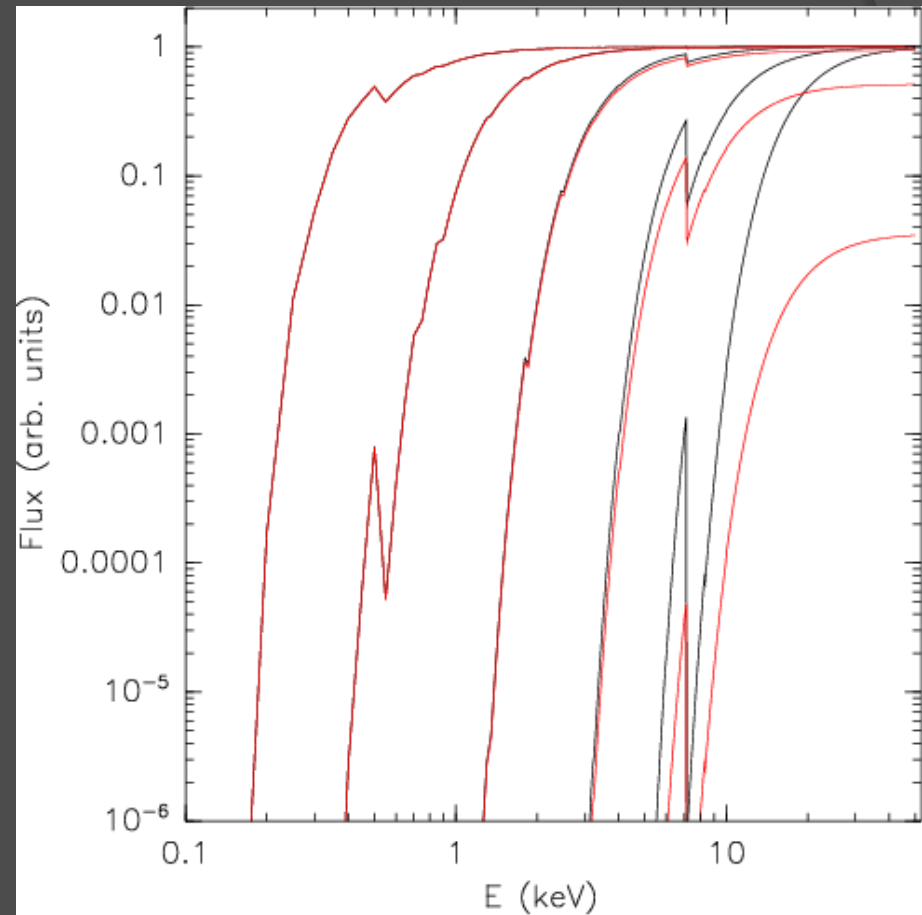


Power-law Spectrum Example

$$F(E) = \exp[-N_H\sigma(E)] NE^{-\alpha}$$

$$\sigma = \sigma_{\text{abs}}$$

$$\sigma = \sigma_{\text{abs}} + \sigma_{\text{T}}$$



Compton Reflection

Photons impact optically-thick material and scatter back out after traversing $\sim \tau$

See George & Fabian (1991)

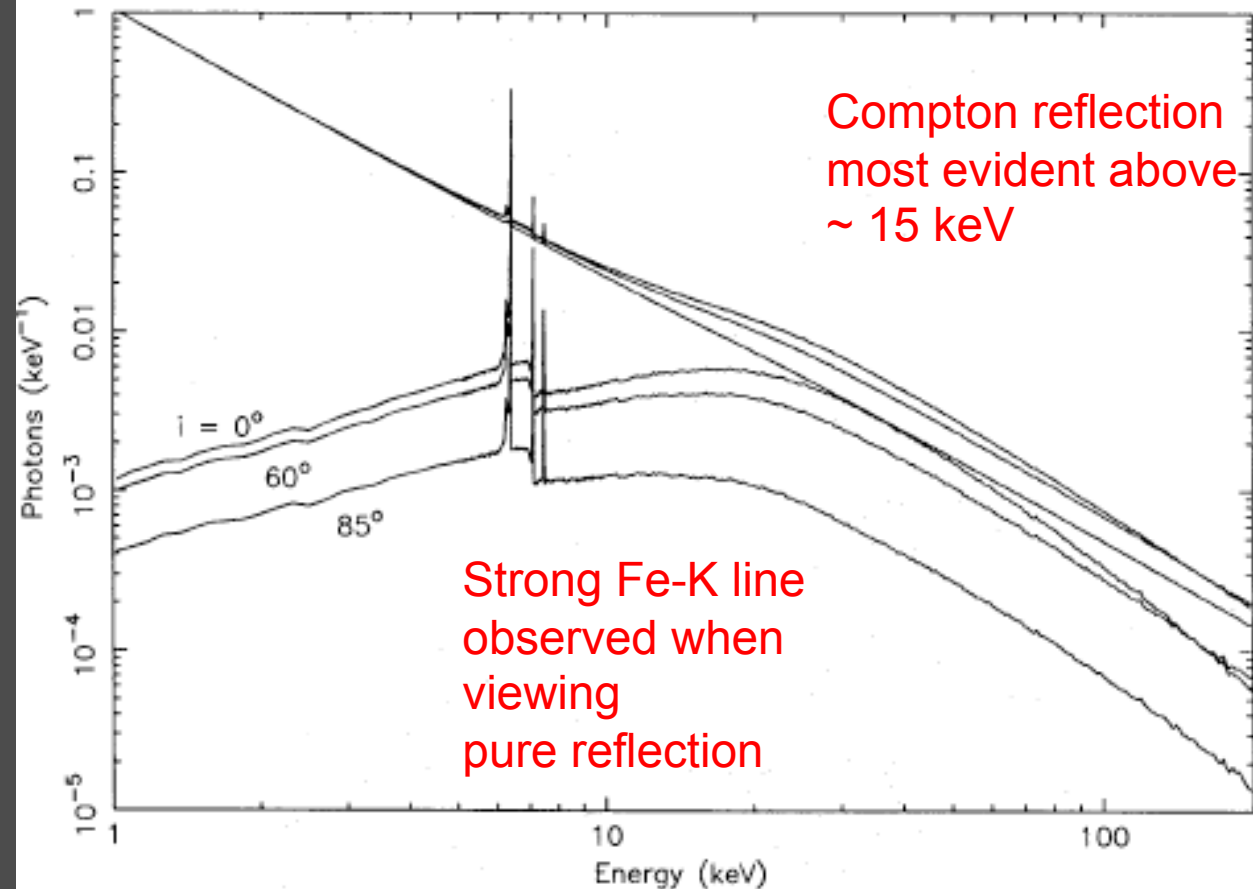
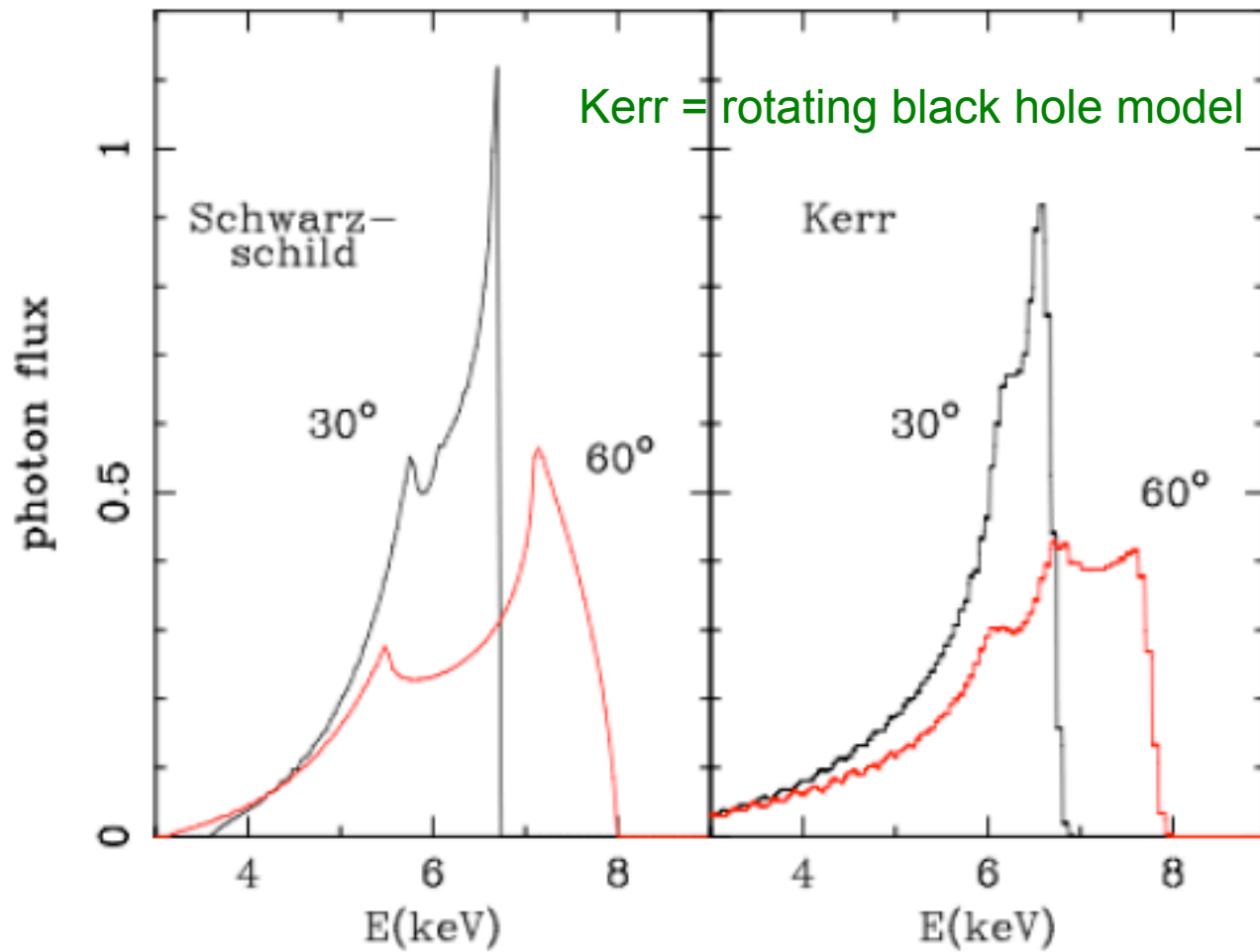
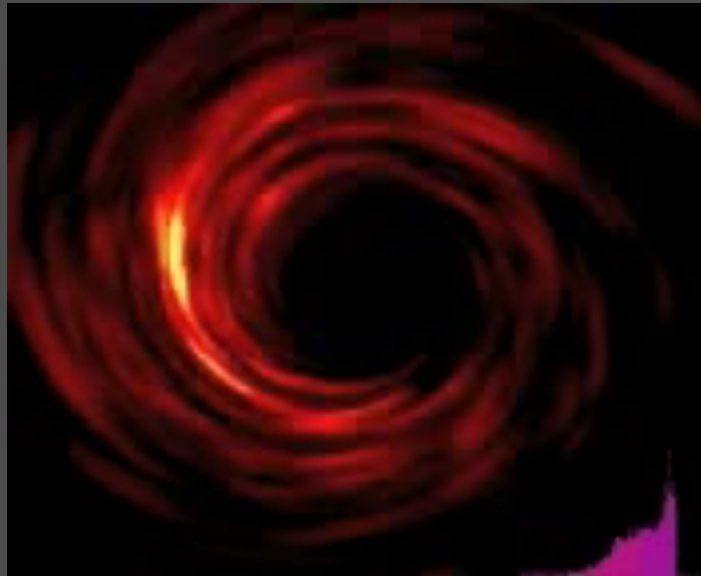


Figure 12. Reflected and composite (reflected + direct) spectra for a flat, optically thick, non-rotating circular slab illuminated by an isotropic source of primary X-rays located a height h above the centre. The spectra shown are for a disc with $r_{\max} = 10^2 h$ and a power-law incident spectrum with $\Gamma = 1.7$, viewed at inclination angles $i = 0^\circ, 60^\circ$ and 85° .

Typical Fe K Emission Line Profiles from Disks





Simulation by Laura Brenneman

Emission Line Equivalent Width

Two measures of line strength:

Line flux

Line equivalent width (EW)

Line flux ~ normalization of the line, depends on distance to AGN

Line EW = line photon flux / continuum at line energy

[line photon flux] = photons/cm²/s

[continuum] = photons/cm²/s/keV

[EW] = keV

EW ~ range in E over which continuum must be integrated to produce photons observed in line

$$\int L(E) dE = \int_{E_0 - EW/2}^{E_0 + EW/2} C(E) dE$$

C = continuum, i.e., $N_{PL} E^{-\Gamma}$

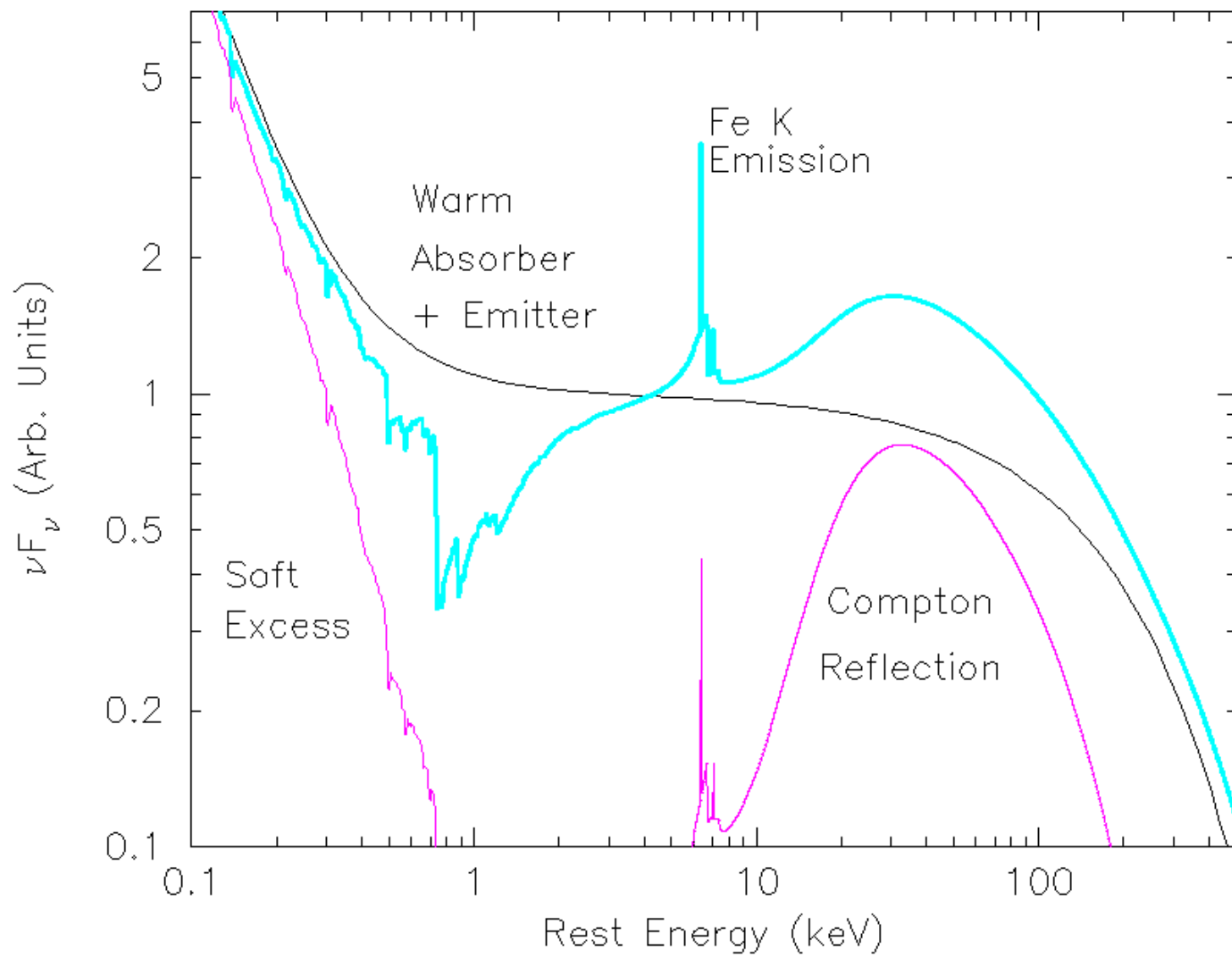
L = line model, e.g., for a Gaussian, $L(E) = N_l \exp[-(E-E_0)^2/2\sigma^2]$

AGN Fe-K Line EWs

- In Seyfert 1s, Fe-K line EWs tend to be ~ 100-400 eV
- In Seyfert 2s, Fe-K line EWs tend to be ~ 100-2000 eV
 - Fe-K EW \gg 400 eV is a strong indication of an obscured central source
 - Absence of a high-EW line does not rule out heavy obscuration
 - Line could be washed out by scattered continuum, continuum outside of the AGN, there is no line of sight to reflecting surfaces (e.g., a spherical covering rather than toroidal, etc.)

Other AGN features

- ⦿ Ionized gas emission lines
 - Photo-ionized outflows
 - Collisionally-ionized gas (star formation)
 - CCD resolution is not sufficient to distinguish these
- ⦿ Ionized absorber/emitter
 - “warm” absorbers: Oxygen edges around 0.8 keV
- ⦿ Soft excess
 - Various models under debate, was thought to be tail of disk blackbody emission
- ⦿ Hot spots: narrow, often transient, emission lines seen near Fe-K



Other Complications

- ⦿ In practice a simple power-law spectrum is only observed when there are low numbers of counts
- ⦿ In Seyfert 2s, there is often mixed scattered, reflected and direct flux (for a recent example, see LaMassa et al. 2010)
 - Obscured sources tends to have flatter spectra: lower power-law slope or hard X-ray colors

X-ray Spectral Analysis

- Energy of each event recorded as a “pulse height amplitude” (PHA)

$$\text{PHA} = aE + b$$

a = gain, b = zero point

Tools like XSPEC can also fit for gain (a,b)

Spectral resolution = error in measuring E,
mainly due counting statistics of ejected
electrons

$$\sigma_{\text{PHA}} = [n^2 + fE]^{0.5} \quad (n^2 = \text{noise term})$$

Spectral Response

$$m(h) = T \int dE \frac{F(E)}{E} A(E) R(E, h)$$

$m(h)$ = expected number of counts at PHA value h

T = exposure time

$A(E)$ = “effective” area of instrument (cm^2)

= geometric area reduced by any attenuation of flux

$R(E, h)$ = line response function = probability of observing photon of energy E at spectral channel h

Spectral Response in Practice

$$m(h) = T \sum_i \Delta E_i \frac{F(E_i)}{E_i} A_i R_{i,h}$$

Pulse height (h) is quantized (by onboard electronics), effective area A computed as a vector, response fn. R computed as matrix.

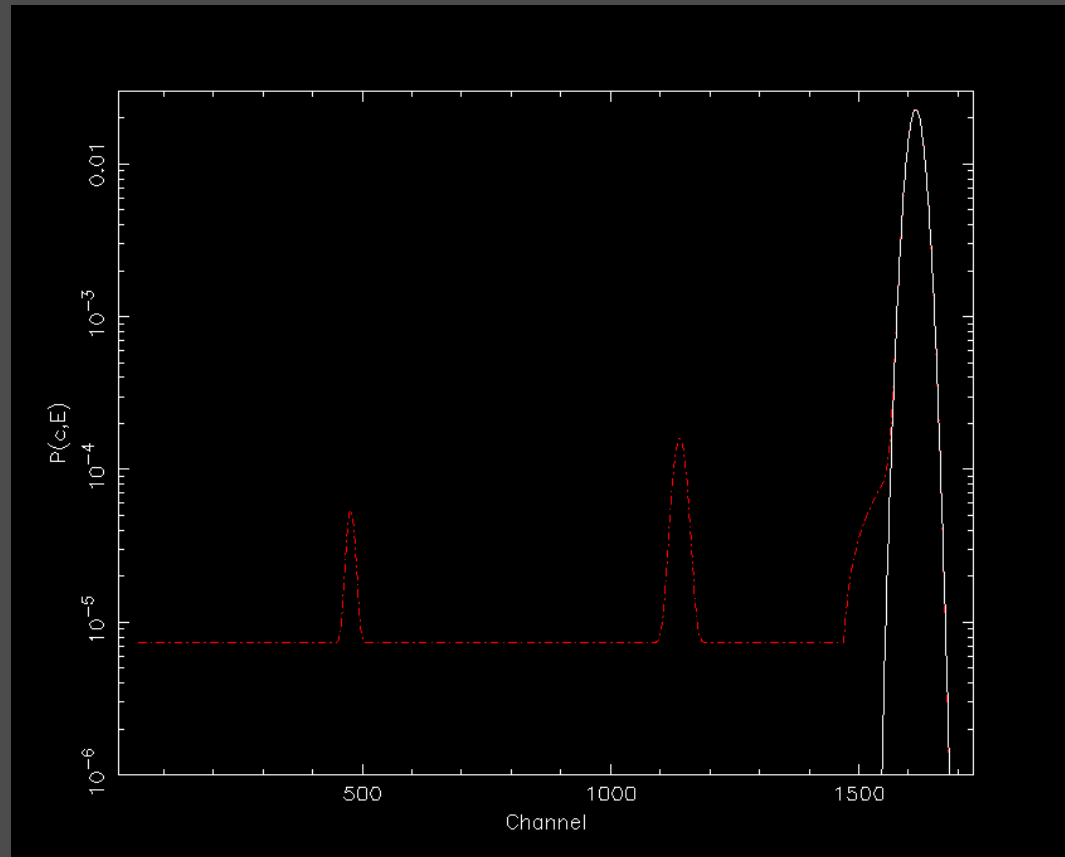
Efficiency of detector QE (“quantum efficiency”) included either in

A ($\sum_h R_{i,h} = 1$) or R ($\sum_h R_{i,h} = \text{QE}$).

Spectral Response (Imaging)

- Geometric area in $A(E)$ is due to mirror, attenuation due to reflection efficiency + absorption in telescope (mirror, windows, coatings, etc.)
- Line response function is \sim Gaussian for CCD detectors

Suzaku CCD Line Response at 5.9 keV



X-ray Spectral Fitting

$$m(h) = T \sum_i \Delta E_i \frac{F(E_i)}{E_i} A_i R_{i,h}$$

- ⊙ The spectral response equation cannot be inverted in a stable way (esp. for X-ray astronomy where there are typically low numbers of photons in each spectral bin)
 - Same problem as trying to “clarify” a blurry picture
- ⊙ Can we fit spectral features directly and ignore R?
 - Sometimes for high-resolution spectra, but not with low (CCD, CZT, etc) spectra or else many fit parameters will be wrong
- ⊙ Alternative: forward fitting
 - Vary model, convolve with response to get predicted counts per spectral bin, compare model prediction with data, rinse and repeat

X-ray Spectral Forward Fitting

- ⦿ Need to minimize difference between $m(h)$ and $c(h)$ (net observed counts = total - background $T(h) - b(h)$)
- ⦿ Two conventional approaches
 - Bin observed spectrum to 10-20 counts per bin so that Gaussian statistics apply (i.e., error in spectral bin $h = \sigma(h) = T(h)^{-0.5}$), directly subtract background, use χ^2 statistics.
 - Use unbinned spectrum, ignore or model background, use Poisson statistics
 - Hybrid: include background as measured but part of model:
 - $P[T(h) \mid m(h) + b(h)]$
 - Probability of observing $T(h)$ total counts given model m and background b (estimated from data)

Gaussian case:

Prob. of observing $c(h)$ for model $m(h)$:

$$P \propto \prod_h \exp[-(c(h) - m(h))^2 / (2\sigma(h)^2)]$$

Maximizing P same as minimizing $-\log(P)$

$$-\log(P) = \sum_h [c(h) - m(h)]^2 / (2\sigma(h)^2)$$

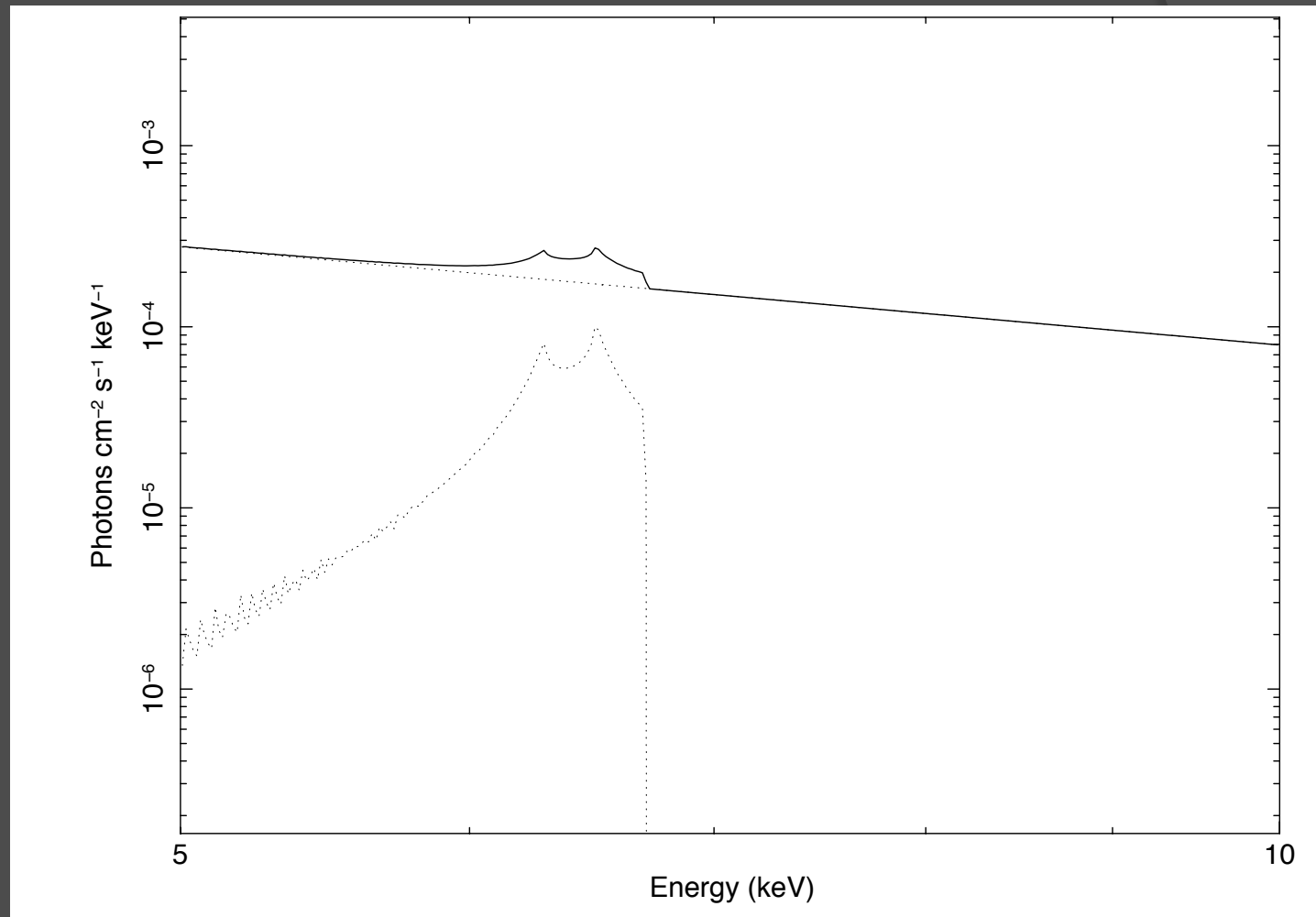
Poisson case:

$$P = \prod_h \text{Poisson}(T(h), m(h)+b(h))$$

Multiple techniques for optimizing fit statistic and getting confidence regions (Aneta's talk). My personal preference is to use c-statistic with Marquardt-Levenberg minimization and ΔC for errors, then verify with simulations and/or Bayesian MCMC analysis, time-permitting

XSPEC “diskline” model

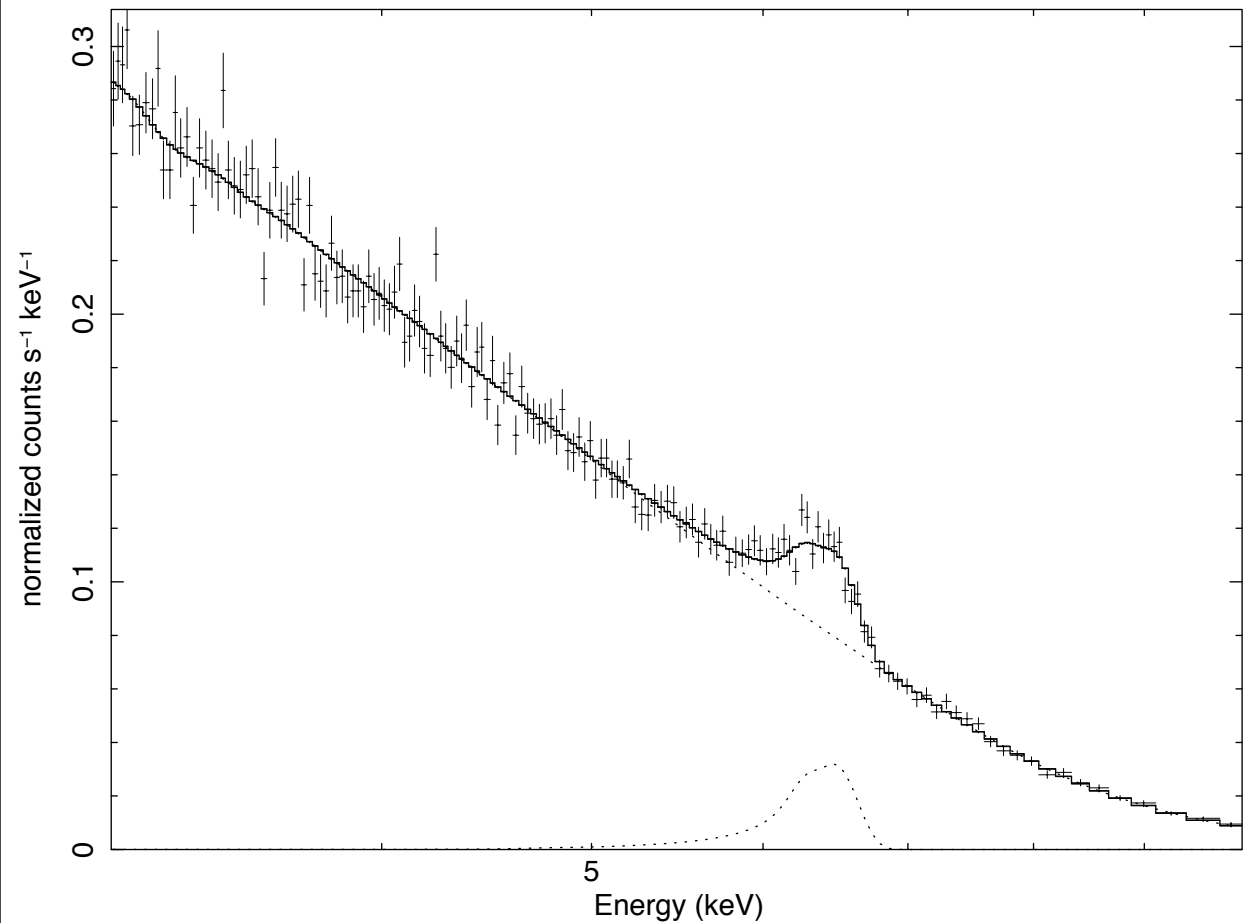
EW = 250 eV
Power-law
with $\Gamma = 1.8$



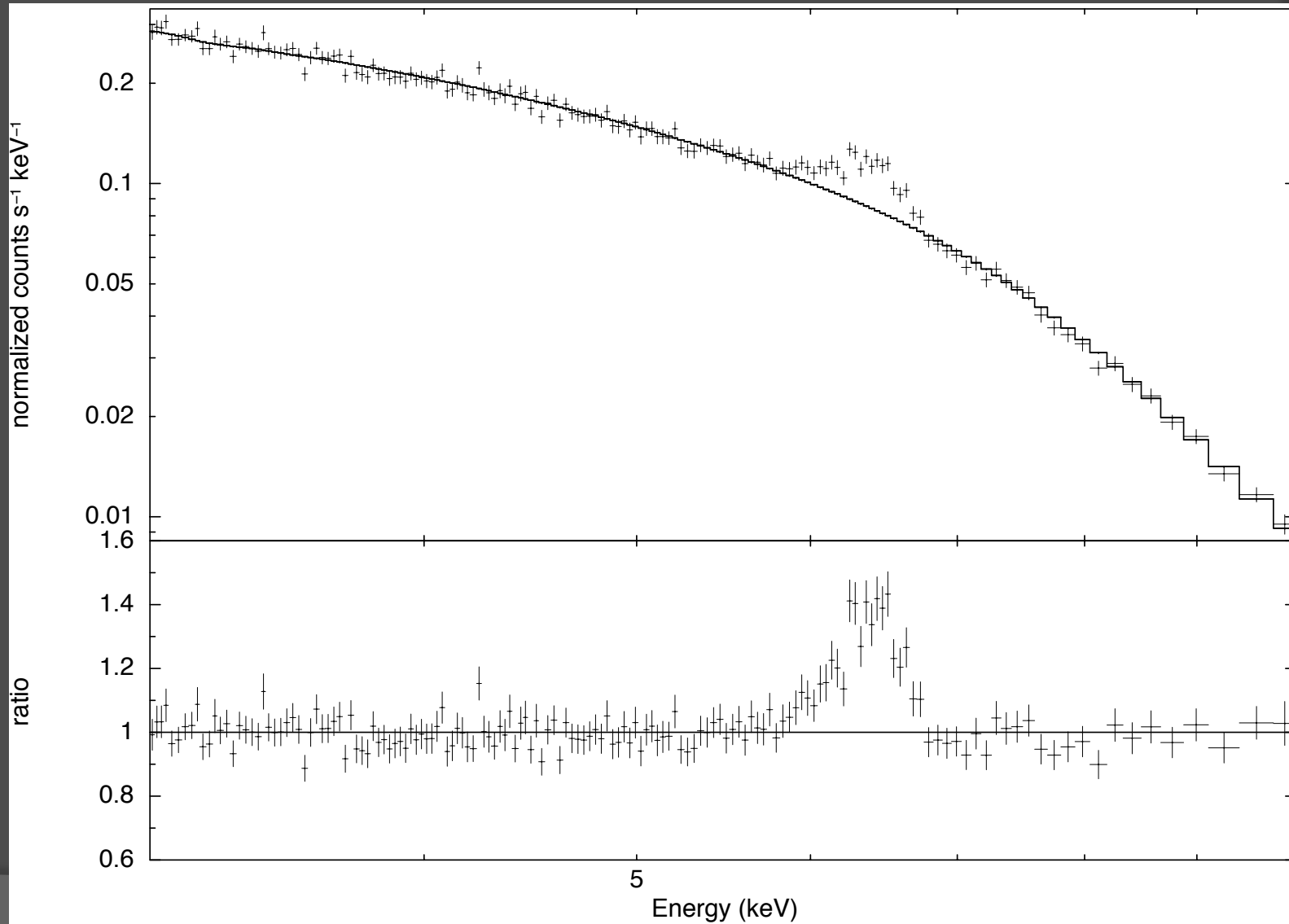
Suzaku Front-Illuminated CCD Simulation

$F(2-10) = 1.7 \times 10^{-11}$ ergs
 $\text{cm}^{-2} \text{s}^{-1}$

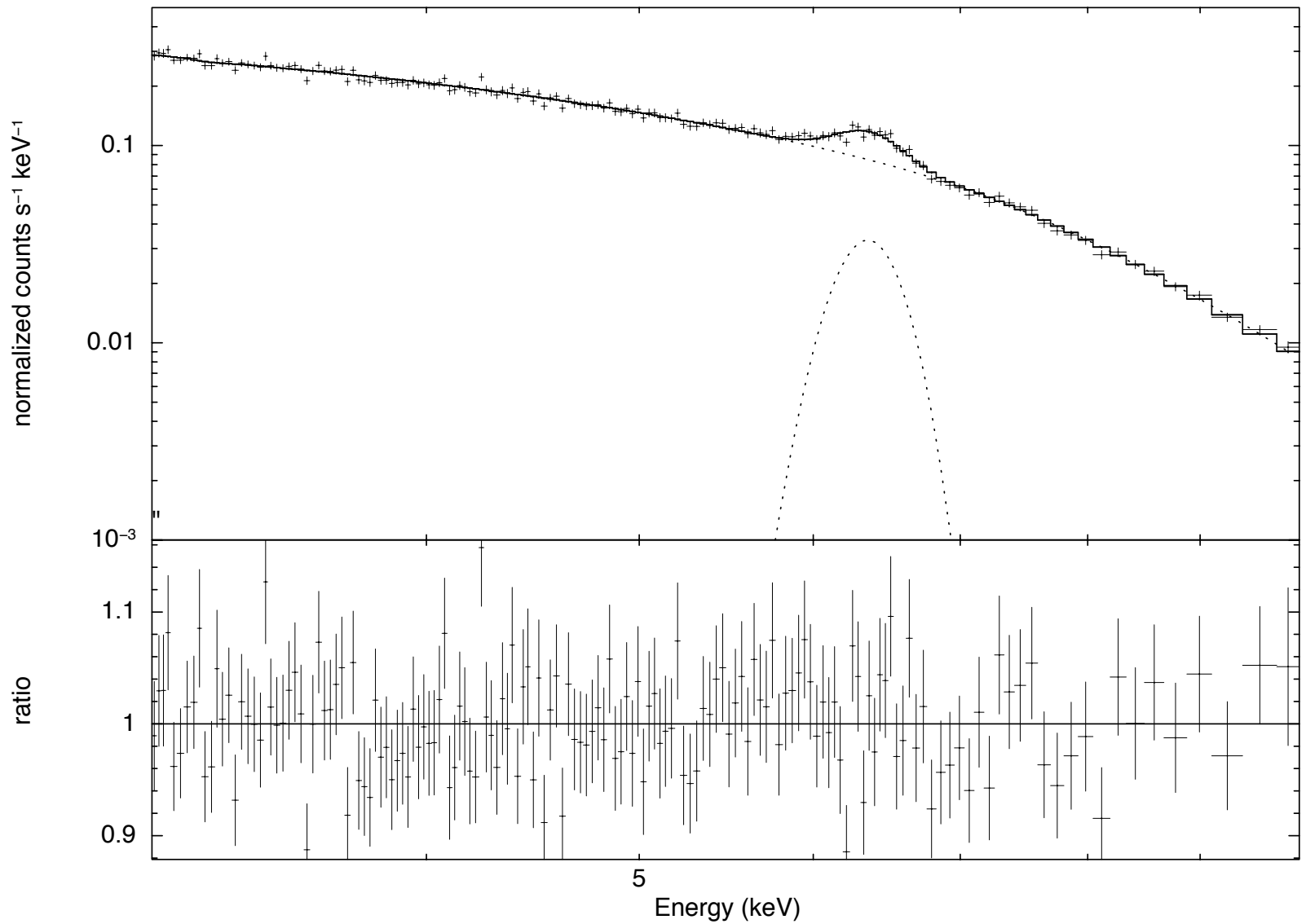
100 ks simulation using
“fakeit” in XSPEC, no
background



Power-law only fit



Power-law plus Gaussian fit



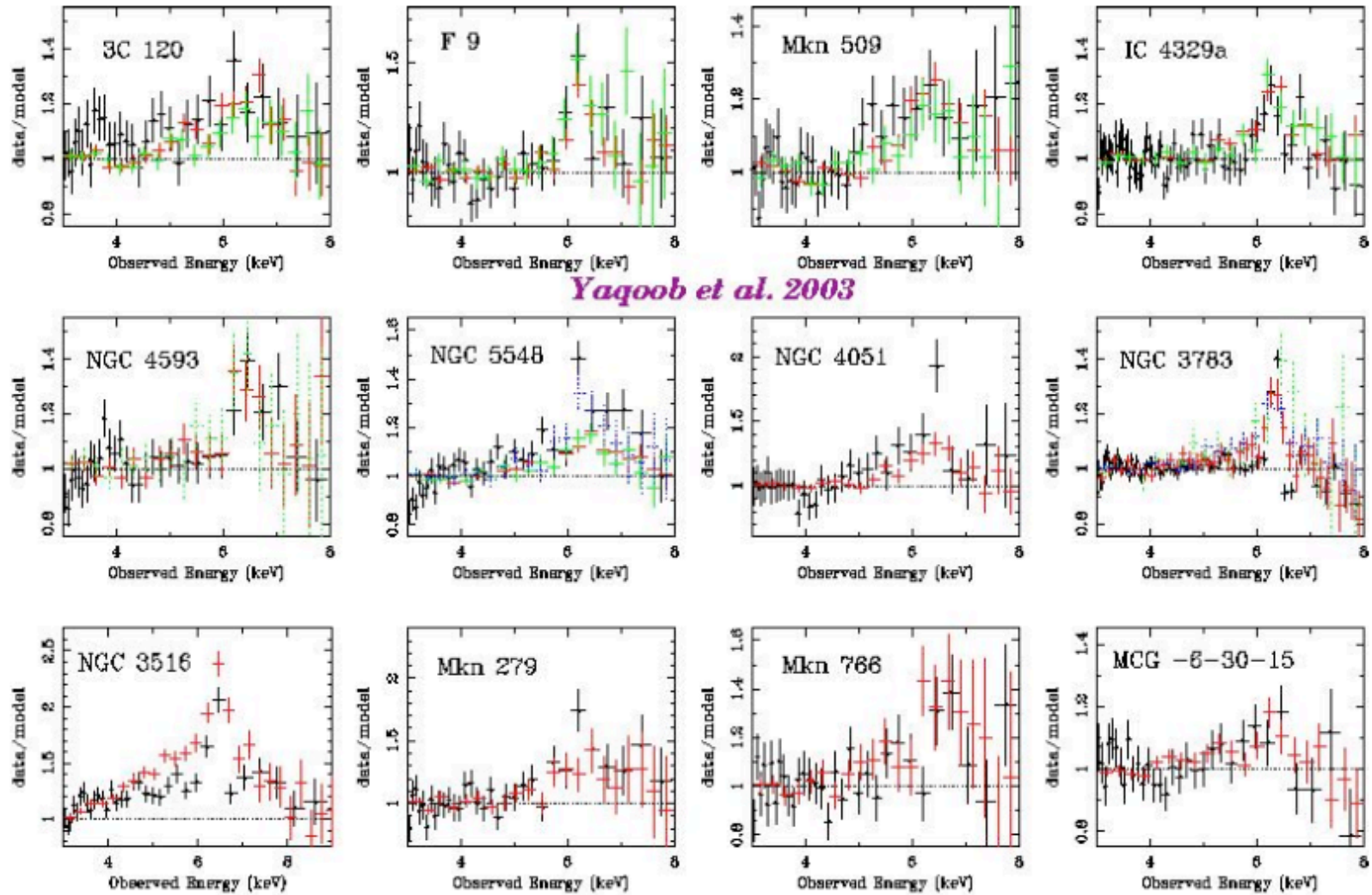
C-statistic for power-law fit: 1365

C-statistic for power-law + gaussian fit: 984

Line physical width from fit: 0.20 (0.17-0.24) keV

N.B. error based on $\Delta C = 4.6$, not strictly statistically-correct (Aneta's talk!) but simulations would probably show this is not far off (e.g., Yaqoob 1998: error on EW can be approximated by scaling error on line norm).

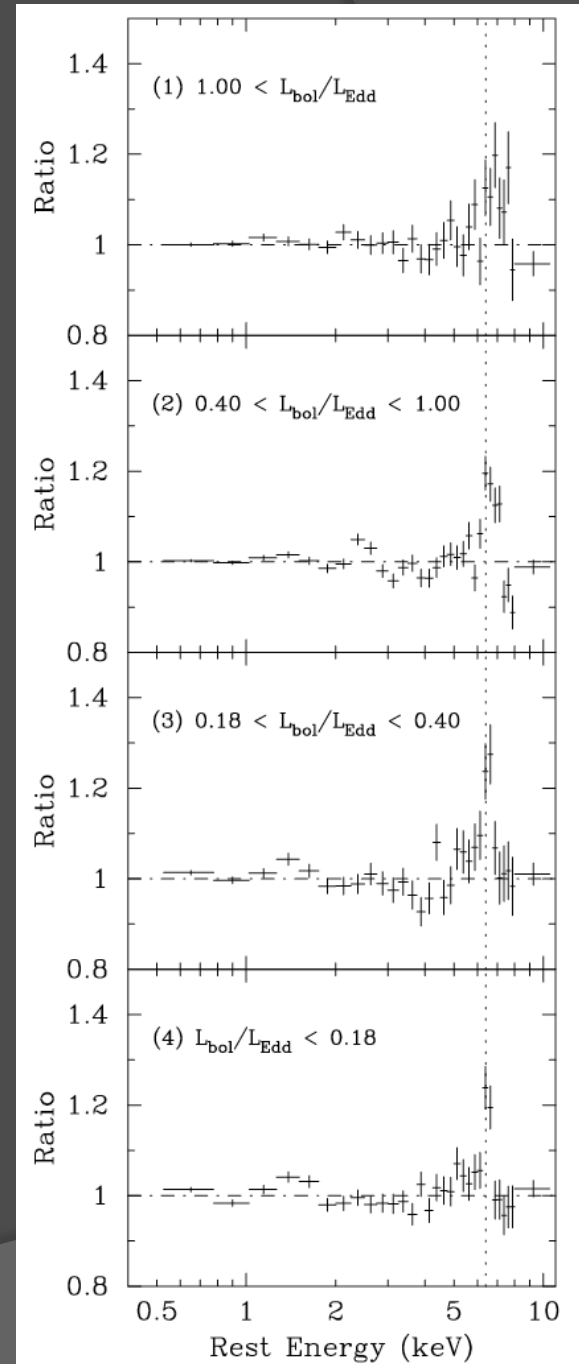
Upshot: a 100 ks Suzaku observation of this hypothetical source might show that there is a broad (physical width $>$ instrumental resolution) Fe-K line but not that this is exclusively consistent with a theoretical disk line



Yaqoob et al. 2003

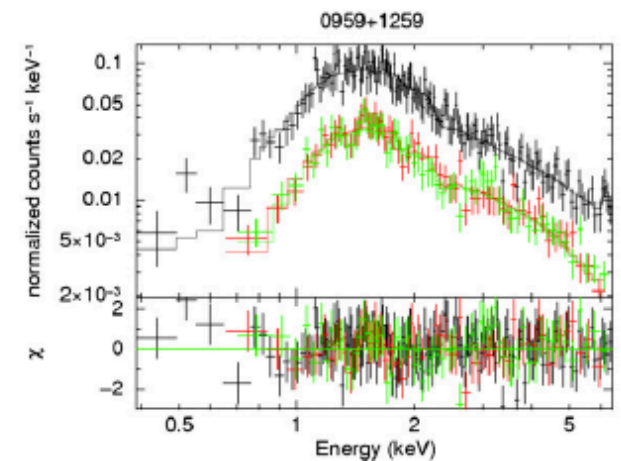
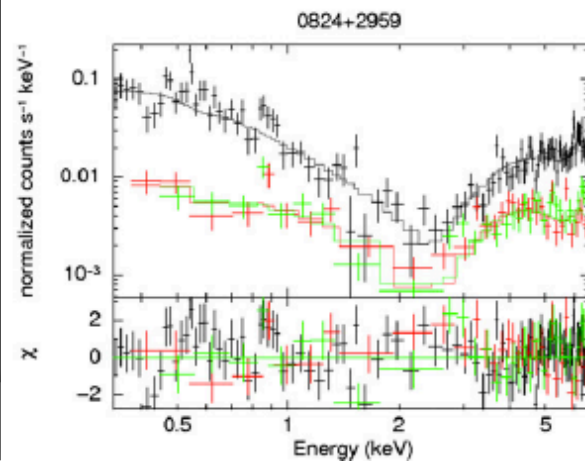
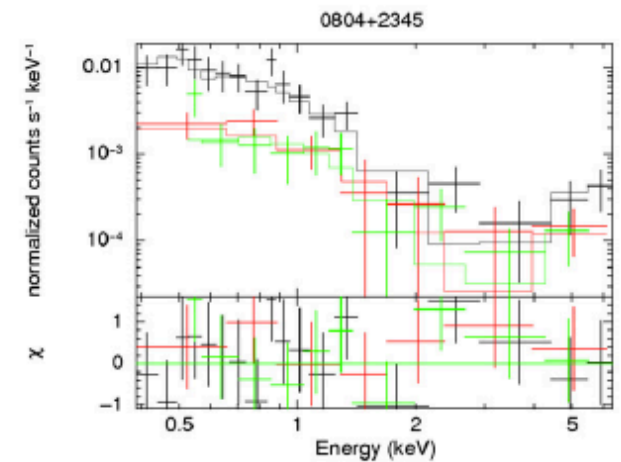
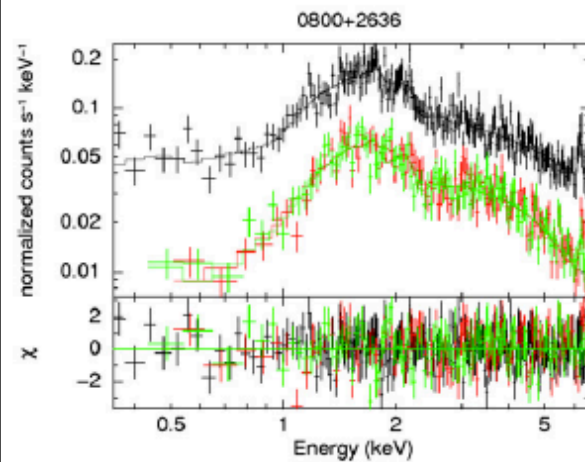
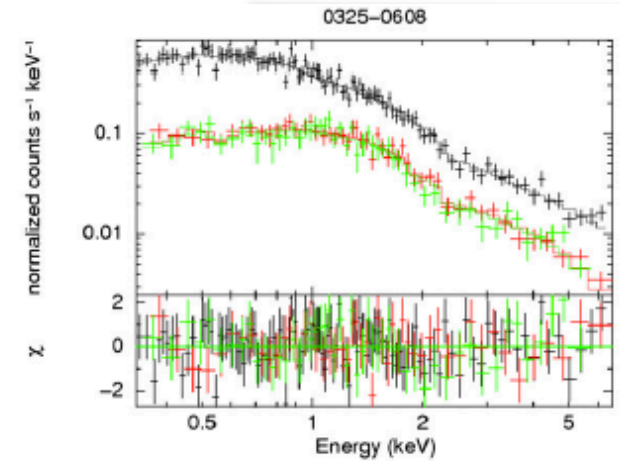
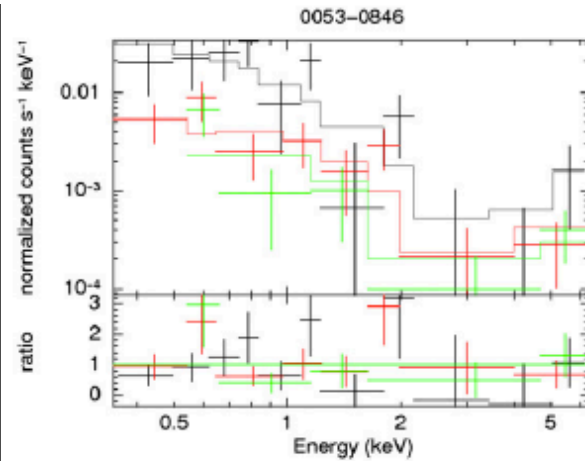
Chandra HEG (BLACK) vs. ASCA S0+S1 (COLORED)

Dependence of Fe-K strength and shape on
Accretion rate (Inoue, Terashima, & Ho 2007)



Range of X-ray spectra observed from a complete optically-selected sample of Seyfert 2s (LaMassa et al. 2010)

Fit well with partial covering models, but could soft components be thermal emission? Ionized outflows not directly tied to intrinsic power-law? Need to use physical intuition, background knowledge e.g., star formation very rarely produced luminosities $> 10^{42}$ ergs s^{-1}



XSPEC Models (similar in other fitting packages)

powerlaw – obvious

phabs – absorption not including scattering

plcabs – absorbed power-law including scattering but in an approximate way only valid up to ~ 15 keV, assumes spherical obscuration

pexrav – Compton reflection

gaussian – obvious

diskline, laor(2), kerrdisk – accretion disk line models

To emulate a partial covering (multiple absorbers and scattering), use:

phabs * (const*powerlaw + plcabs)

Optionally tie power-law index in plcabs model to powerlaw model, which would represent elastic scattering (i.e., assumes a highly ionized plasma is acting as a mirror)

const = constant term for scattering fraction, typically 1-10%

Fitting Low-resolution AGN spectra in practice

- ⦿ Lack of spectral resolution literally blurs distinction between models
- ⦿ Low numbers of photons often effectively lowers the spectral resolution (e.g., information content of 100 photons over a 10 keV range will low whether data are physically binned or not)
- ⦿ Care must be taken in assessing significance of features and in model selection (statistics talk later)

Potential Exercises

- ⦿ Download data from classic Seyfert galaxies (e.g., NGC 3227, Fairall 9, NGC 2992, NGC 4151, Mrk 3) and fit power-law models to 2-10 keV spectrum
 - Watch out for pileup!
 - Add additional absorber, esp. for Sy 2s
 - Compare diskline and gaussian fits to Fe-K
 - Does Fe-K EW vary between observations?
- ⦿ Repeat Fe-K diskline simulation shown here: how many counts are needed before diskline becomes statistically distinct from a broad Gaussian?
- ⦿ Simulate partial covering models at various numbers of counts (100, 500, 1000, 5000)
 - Fit with a simple power law, see how “effective” photon index for a simple power-law fit varies with scattering fraction, N_H of the highly absorbed component

Spare Slides

Imaging X-ray Telescopes

- ◎ Grazing-incidence optics
 - Often Au or Ir coatings
- ◎ Detectors
 - Micro-channel plates (1980s-present) - no energy resolution
 - Einstein, Chandra (1999-present)
 - Imaging proportional counters (1980s) - poor energy res.
 - Einstein, EXOSAT, ROSAT
 - CCDs (1990s-present) - moderate energy res.
 - ASCA, Chandra, XMM-Newton, Suzaku, Swift XRT
 - Gratings (effectively 1999-present) – very good energy res.
 - Chandra, XMM-Newton
 - Calorimeters (2010s-?) - good energy res.
 - Suzaku (but died just before observations started)
 - Astro-H 2014 launch
 - IXO re-envisioned as Athena (ESA) and Con-X-R (US), >2020 launch

Non-Imaging X-ray Detectors

- ⦿ X-rays detected via ionization
 - Total charge liberated proportional to energy of photon
 - “Proportional counters”
 - Individual photon “events” recorded
- ⦿ Collimators used to limit field of view (FOV) and reduce background
- ⦿ Each observation results in spectra (flux vs. energy) and light curves (flux vs. time)
- ⦿ Still used today (NASA Swift, RXTE, NASA/JAXA Suzaku)